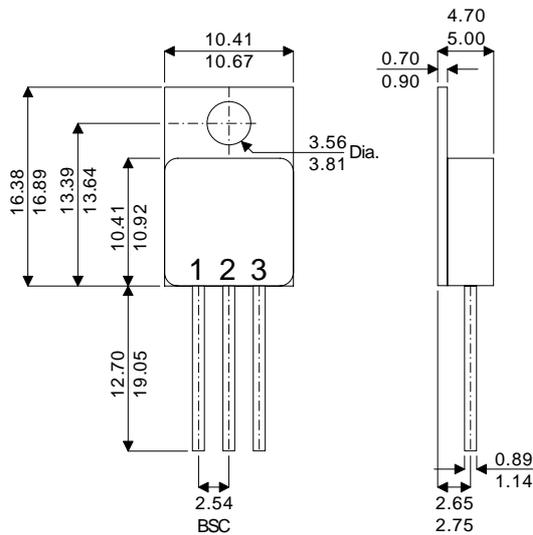


**MECHANICAL DATA**

Dimensions in mm (inches)



**TO-220M – Metal Package**

Pad 1 – Gate      Pad 2 – Drain      Pad 3 – Source

**N-CHANNEL  
POWER MOSFET  
FOR HI-REL  
APPLICATIONS**

$V_{DSS}$             **400V**  
 $I_{D(cont)}$         **6.9A**  
 $R_{DS(on)}$         **0.55Ω**

**FEATURES**

- HERMETICALLY SEALED TO-220 METAL PACKAGE
- SIMPLE DRIVE REQUIREMENTS
- LIGHTWEIGHT
- SCREENING OPTIONS AVAILABLE
- ALL LEADS ISOLATED FROM CASE

**ABSOLUTE MAXIMUM RATINGS** ( $T_{case} = 25^{\circ}C$  unless otherwise stated)

$V_{GS}$	Gate – Source Voltage	$\pm 20V$
$I_D$	Continuous Drain Current ( $V_{GS} = 0, T_{case} = 25^{\circ}C$ )	6.9A
$I_D$	Continuous Drain Current ( $V_{GS} = 0, T_{case} = 100^{\circ}C$ )	4.4A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	27A
$P_D$	Power Dissipation @ $T_{case} = 25^{\circ}C$	60W
	Linear Derating Factor	0.48W/ $^{\circ}C$
$T_J, T_{stg}$	Operating and Storage Temperature Range	-55 to 150 $^{\circ}C$
$T_L$	Package Mounting Surface Temperature (for 5 sec)	300 $^{\circ}C$
$R_{\theta JC}$	Thermal Resistance Junction to Case	2.1 $^{\circ}C/W$ max.

**Notes**

1) Pulse Test: Pulse Width  $\leq 300ms, \delta \leq 2\%$

**ELECTRICAL CHARACTERISTICS** ( $T_{amb} = 25^{\circ}\text{C}$  unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>STATIC ELECTRICAL RATINGS</b>					
$BV_{DSS}$ Drain – Source Breakdown Voltage	$V_{GS} = 0$ $I_D = 1\text{mA}$	400			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$ Temperature Coefficient of Breakdown Voltage	Reference to $25^{\circ}\text{C}$ $I_D = 1\text{mA}$		0.46		$\text{V}/^{\circ}\text{C}$
$R_{DS(on)}$ Static Drain – Source On–State Resistance <sup>1</sup>	$V_{GS} = 10\text{V}$ $I_D = 4.4\text{A}$			0.55	$\Omega$
	$V_{GS} = 10\text{V}$ $I_D = 6.9\text{A}$			0.63	
$V_{GS(th)}$ Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 250\mu\text{A}$	2		4	V
$g_{fs}$ Forward Transconductance <sup>1</sup>	$V_{DS} \geq 15\text{V}$ $I_{DS} = 4.4\text{A}$	4.9			$\text{S}(\bar{\omega})$
$I_{DSS}$ Zero Gate Voltage Drain Current	$V_{GS} = 0$ $V_{DS} = 0.8BV_{DSS}$ $T_J = 125^{\circ}\text{C}$			25	$\mu\text{A}$
				250	
$I_{GSS}$ Forward Gate – Source Leakage	$V_{GS} = 20\text{V}$			100	nA
$I_{GSS}$ Reverse Gate – Source Leakage	$V_{GS} = -20\text{V}$			-100	
<b>DYNAMIC CHARACTERISTICS</b>					
$C_{iss}$ Input Capacitance	$V_{GS} = 0$		1400		pF
$C_{oss}$ Output Capacitance	$V_{DS} = 25\text{V}$		350		
$C_{riss}$ Reverse Transfer Capacitance	$f = 1\text{MHz}$		230		
$Q_g$ Total Gate Charge <sup>1</sup>	$V_{GS} = 10\text{V}$ $I_D = 6.9\text{A}$ $V_{DS} = 0.5BV_{DSS}$	32		65	nC
$Q_{gs}$ Gate – Source Charge <sup>1</sup>	$V_{GS} = 10\text{V}$ $I_D = 6.9\text{A}$	2.2		10	nC
$Q_{gd}$ Gate – Drain (“Miller”) Charge <sup>1</sup>	$V_{DS} = 0.5BV_{DSS}$	13.8		40.5	
$t_{d(on)}$ Turn–On Delay Time	$V_{DD} = 200\text{V}$			25	ns
$t_r$ Rise Time	$I_D = 6.9\text{A}$			92	
$t_{d(off)}$ Turn–Off Delay Time	$R_G = 9.1\Omega$			79	
$t_f$ Fall Time	$V_{GS} = 10\text{V}$			58	
<b>SOURCE – DRAIN DIODE CHARACTERISTICS</b>					
$I_S$ Continuous Source Current				6.9	A
$I_{SM}$ Pulse Source Current <sup>2</sup>				27	
$V_{SD}$ Diode Forward Voltage	$I_S = 6.9\text{A}$ $T_C = 25^{\circ}\text{C}$ $V_{GS} = 0$			1.5	V
$t_{rr}$ Reverse Recovery Time	$I_S = 6.9\text{A}$ $T_J = 25^{\circ}\text{C}$			600	ns
$Q_{rr}$ Reverse Recovery Charge	$d_i / d_t \leq 100\text{A}/\mu\text{s}$ $V_{DD} \leq 50\text{V}$			5.6	$\mu\text{C}$
$t_{on}$ Forward Turn–On Time		Negligible			
<b>PACKAGE CHARACTERISTICS</b>					
$L_D$ Internal Drain Inductance (6mm down drain lead to centre of die)			8.7		nH
$L_S$ Internal Source Inductance (6mm down source lead to centre of source bond pad)			8.7		

**Notes**

- 1) Pulse Test: Pulse Width  $\leq 300\text{ms}$ ,  $\delta \leq 2\%$
- 2) Repetitive Rating – Pulse width limited by maximum junction temperature.